Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/715,447	FUJII ET AL.
Examiner	Art Unit
Sanh D. Phu	2618

SEADONED						
	SEARCHED					
Class	Subclass	Date	Examiner			
		7				
455	41.2	6/21/56	50			
	88		ĵ			
	410					
342	42					
	42 44 50					
	50	J	J			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	-				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST	6/21/0b	de la		